Conference Paper Title

Fabian Posch
Institute for Computer Engineering
TU Wien
Vienna, Austria
fabian.posch@student.tuwien.ac.at

Florian Huemer
Institute for Computer Engineering
TU Wien
Vienna, Austria
fhuemer@ecs.tuwien.ac.at

Andreas Steininger
Institute for Computer Engineering
TU Wien
Vienna, Austria
steininger@ecs.tuwien.ac.at

Rajit Manohar
Computer Systems Lab
Yale University
New Haven, CT 06520, USA
rajit.manohar@yale.edu

Abstract—**ACT is a very versatile and powerful tool for design, simulation and manufacturing of asynchronous circuits. When fault tolerance is a priority, being able to simulate the possible effects as part of the design process can be a huge boon.**
In this paper we present an augmentation of ACT which allows flexible and comprehensive (transient) fault injection. Key features of this tool are native integration into the existing language framework, distributed computation to speed up wait times, as well as an improved fault distribution model compared to previous attempts. We describe the fault model we targeted, the implementation, issues which had to be overcome, as well as an application example to demonstrate the use and capabilities of the tool.

Index Terms—**NEEDS TO BE CHANGED**

This is a test reference for the paper [1]

REFERENCES

[1] Altera. "Introduction to Single-Event Upsets". In: *WP-01206-1.0* (Sept. 2013). URL: https://cdrdv2-public.intel.com/650466/wp-01206-introduction-single-event-upsets.pdf.